## Notice of References Cited Application/Control No. 09/763,411 Examiner Enrique L Santiago Applicant(s)/Patent Under Reexamination HANAI ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,634,948 B1	10-2003	Hayashi et al.	463/42
	В	US-			
	C	US-			·
	ם	US-			
	E	US-			
	F	US-			
	G	US-			
	H ·	US-			
	ı	US-			
	J	US-			
	К	US-			
	٦	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Р					
	O					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	
	٧	
	W	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.